

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Christoper Ausschnitt	Dated: January 12, 2010
Serial Number: 10/596,614	Examiner: Young, Christopher G.
Filing date: June 19, 2006	Group Art Unit: 1795 Confirmation No.: 8458
Title: Differential Critical Dimension and Overlay Metrology Apparatus and Measurement Method	IBM Corporation D/18G, B/321, Zip 482 2070 Route 52 Hopewell Junction, NY 12533-6531

RESPONSE TO NOTICE OF DRAWING INCONSISTENCY WITH SPECIFICATION

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

Sir:

In response to the Notice of Drawing Inconsistency with Specification dated December 31, 2009, Applicant respectfully submits the following:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Drawings are shown on the "REPLACEMENT SHEET" attached to this paper.

Remarks begin on page 3 of this paper.